

Penetration and energy-loss theory of electrons in solid

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Citation Report

#	ARTICLE	IF	CITATIONS
1	Secondary electron emission due to primary and backscattered electrons. Journal Physics D: Applied Physics, 1972, 5, 1727-1742.	1.3	137
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5	Transmission, energy distribution, and SE excitation of fast electrons in thin solid films. Physica Status Solidi A, 1974, 26, 525-535.	1.7	241
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